

DCR820N65

Phase Control Thyristor

Preliminary Information



DS5923-1.3 June 2008 (LN 26210)

FEATURES

- Double Side Cooling
- High Surge Capability

APPLICATIONS

- Medium Voltage Soft Starts
- High Voltage Power Supplies
- Static Switches

VOLTAGE RATINGS

Part and Ordering Number	Repetitive Peak Voltages V _{DRM} and V _{RRM} V	Conditions
DCR820N65* DCR820N60 DCR820N55 DCR820N50	6500 6000 5500 5000	$\begin{split} T_{vj} &= \text{-}40^\circ\!\text{C to }125^\circ\!\text{C},\\ I_{DRM} &= I_{RRM} = 200\text{mA},\\ V_{DRM}, V_{RRM}t_p &= 10\text{ms},\\ V_{DSM}\&V_{RSM} &= \\ V_{DRM}\&V_{RRM} + 100V\\ respectively \end{split}$

Lower voltage grades available. 6200V @ -40° C, 6500V @ 0° C

ORDERING INFORMATION

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

DCR820N65

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.

KEY PARAMETERS

V_{DRM}	6500V
$I_{T(AV)}$	820A
I _{TSM}	12000A
dV/dt*	1500V/μs
dI/dt	200Α/μs

* Higher dV/dt selections available

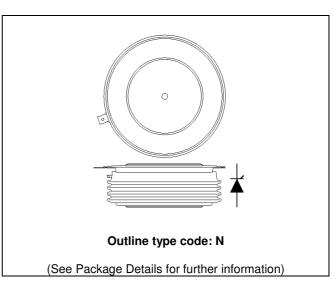


Fig. 1 Package outline



CURRENT RATINGS

T_{case} = 60 °C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
Double Side Cooled				
I _{T(AV)}	Mean on-state current	Half wave resistive load	820	Α
I _{T(RMS)}	RMS value	-	1288	Α
I _T	Continuous (direct) on-state current	-	1090	Α

SURGE RATINGS

Symbol Parameter		Test Conditions	Max.	Units
I _{TSM} Surge (non-repetitive) on-state current		10ms half sine, T _{case} = 125 ℃	12.0	kA
l ² t	I ² t for fusing	$V_R = 0$	0.72	MA ² s

THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
R _{th(j-c)}	Thermal resistance – junction to case	Double side cooled	DC	-	0.0221	∘C/W
		Single side cooled	Anode DC	-	0.041	°C/W
			Cathode DC	-	0.0516	°C/W
R _{th(c-h)}	Thermal resistance – case to heatsink	Clamping force 23 kN Double side		-	0.004	°C/W
		(with mounting compound)	Single side	-	0.008	°C/W
T _{vj}	Virtual junction temperature	On-state (conducting)		-	135	℃
		Reverse (blocking)		-	125	°C
T _{stg}	Storage temperature range			-55	125	℃
Fm	Clamping force			20.0	25.0	kN





DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
I _{RRM} /I _{DRM}	Peak reverse and off-state current	At V _{RRM} /V _{DRM} , T _{case} = 125℃	At V _{RRM} /V _{DRM} , T _{case} = 125 ℃		200	mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V _{DRM} , T _j = 125℃, ga	ate open	-	1500	V/µs
dl/dt	Rate of rise of on-state current	From 67% V _{DRM} to 2x I _{T(AV)}	Repetitive 50Hz	-	100	A/μs
		Gate source 30V, 10Ω,	Non-repetitive	-	200	A/μs
		t _r < 0.5μs, T _j = 125℃				
V _{T(TO)}	Threshold voltage – Low level	100A to 870A at T _{case} = 125°	C	-	1.0	V
	Threshold voltage – High level	870A to 3000A at T _{case} = 125	5℃	-	1.1847	V
r _T	On-state slope resistance – Low level	100A to 870A at T _{case} = 125℃		-	1.1429	mΩ
	On-state slope resistance – High level	870A to 3000A at T _{case} = 125 ℃		-	0.9472	mΩ
t _{gd}	Delay time	$V_D = 67\% V_{DRM}$, gate source 30V, 10Ω		-	3	μs
	•	t _r = 0.5μs, T _j = 25℃				
tq	Turn-off time	$T_j = 125$ °C, $I_{peak} = 1000$ A, $t_p = V_{RM} = 100$ V, $dI/dt = -5$ A/ μ s,	= 1000us,	600	1000	μs
		$dV_{DR}/dt = 20V/\mu s$ linear to 25	500V			
I _{RR}	Reverse recovery current	$I_T = 1000A$, $t_p = 1000us$, $T_j = 125$ °C, $dI/dt = -5A/\mu s$, $V_R = 100V$		90	120	Α
Qs	Stored charge			2500	4000	μС
IL	Latching current	$T_j = 25$ °C, $V_D = 5$ V		-	3	Α
I _H	Holding current	$T_{j} = 25 ^{\circ}\text{C}, R_{G-K} = \infty, I_{TM} = 500$	0A, I _T = 5A	-	300	mA



GATE TRIGGER CHARACTERISTICS AND RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
V_{GT}	Gate trigger voltage	V _{DRM} = 5V, T _{case} = 25 ℃	1.5	V
V_{GD}	Gate non-trigger voltage	At 50% V _{DRM} , T _{case} = 125 ℃	0.4	V
I _{GT}	Gate trigger current	V _{DRM} = 5V, T _{case} = 25 ℃	250	mA
I _{GD}	Gate non-trigger current	At 50% V _{DRM} , T _{case} = 125℃	15	mA

CURVES

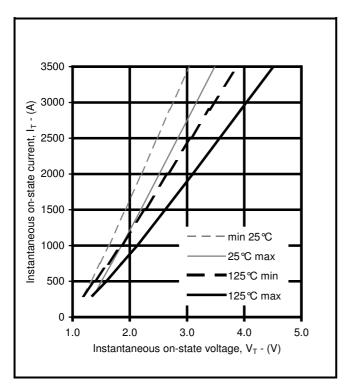


Fig.2 Maximum & minimum on-state characteristics

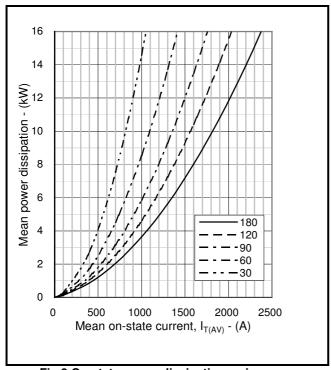
 V_{TM} **EQUATION** Where A = 0.739446 B = 0.018199

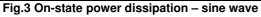
 $V_{TM} = A + Bln (I_T) + C.I_T + D.\sqrt{I_T}$ C = 0.000769

D = 0.017564

these values are valid for $T_j = 125 \,^{\circ}\text{C}$ for $I_T 300 \text{A}$ to 3000A







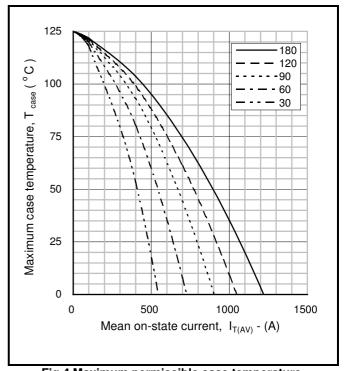


Fig.4 Maximum permissible case temperature, double side cooled – sine wave

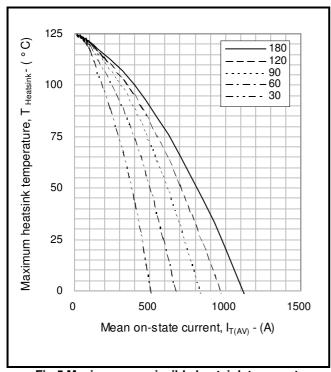


Fig.5 Maximum permissible heatsink temperature, double side cooled – sine wave

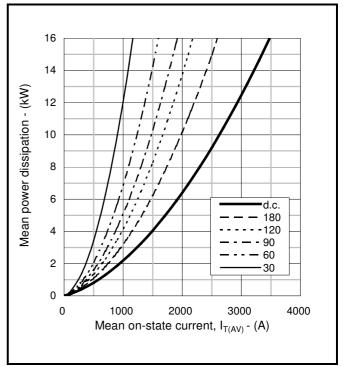
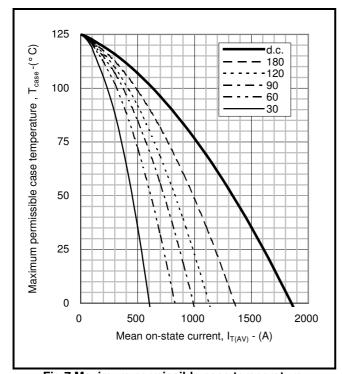
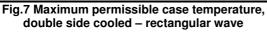


Fig.6 On-state power dissipation - rectangular wave







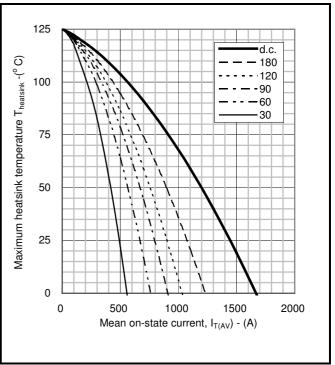
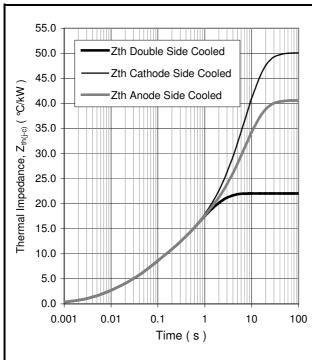


Fig.8 Maximum permissible heatsink temperature, double side cooled – rectangular wave



		1	2	3	4
Double side cooled	R _i (°C/kW)	3.4733	4.9047	9.1463	4.5220
	T _i (s)	0.1457	0.0166	1.2832	0.3767
Anode side cooled	R _i (°C/kW)	7.6674	5.0530	9.7355	27.5992
	T _i (s)	0.2241	0.0169	4.0566	8.2780
Cathode side cooled	R _i (°C/kW)	6.0393	4.2782	5.1301	25.0874
	T _i (s)	0.1356	0.0143	0.6594	7.2358

$$Z_{th} = \sum_{i=1}^{i=4} [R_i \times (1 - \exp(T/T_i))]$$

$\Delta R_{th(j-c)}$ Conduction

Tables show the increments of thermal resistance $R_{\text{th}(j\cdot c)}$ when the device operates at conduction angles other than d.c.

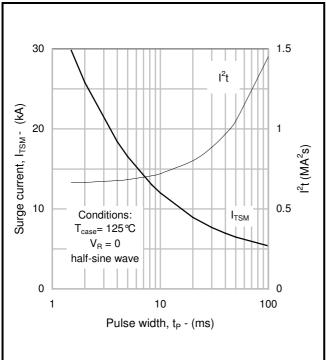
	Double side co			Anode Sic	
	ΔZ_{th} (z)				L
θ°	sine.	rect.		θ°	sine.
180	3.03	2.07		180	3.03
120	3.49	2.95		120	3.49
90	3.99	3.43		90	3.99
60	4.43	3.94		60	4.43
30	4.77	4.49		30	4.76
15	4.02	4 77	1 1	15	4.02

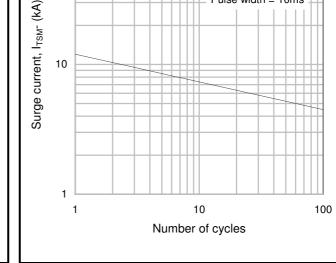
Š	trioue Sidet	thode Sided Cooling			
	ΔZ_{th} (z)				
θ°	sine.	rect.			
180	3.12	2.12			
120	3.61	3.04			
90	4.13	3.54			
60	4.60	4.08			
30	4.96	4.66			
15	5.13	4.97			

Fig.9 Maximum (limit) transient thermal impedance – junction to case (°C/kW)



Conditions: Tcase = 125 °C $V_R = 0$ Pulse width = 10ms

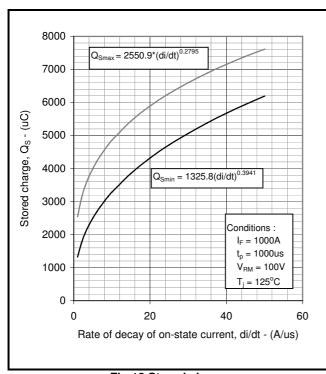


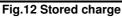


100

Fig.10 Single-cycle surge current

Fig.11 Multi-cycle surge current





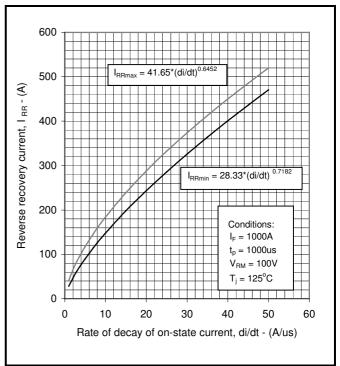


Fig.13 Reverse recovery current

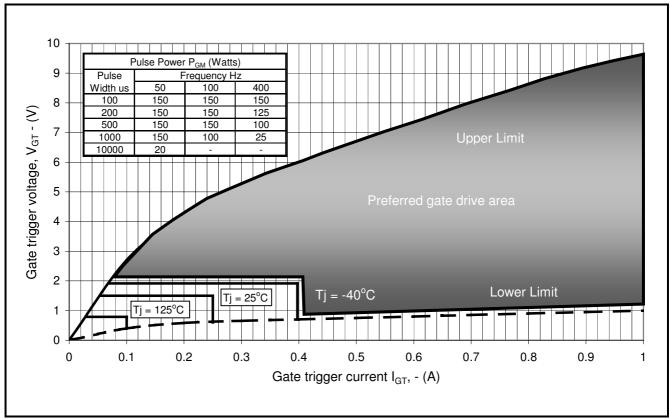


Fig14 Gate Characteristics

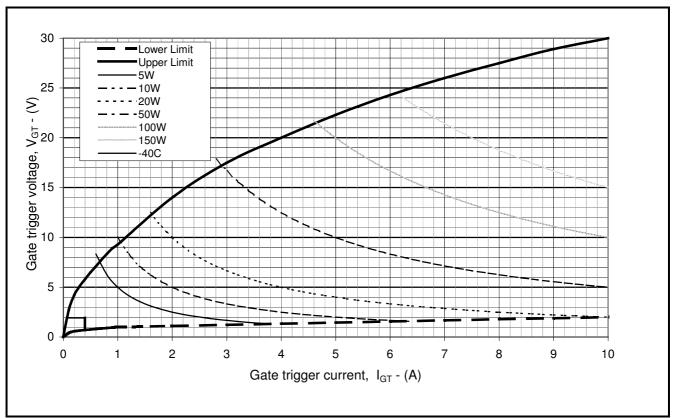


Fig. 15 Gate characteristics

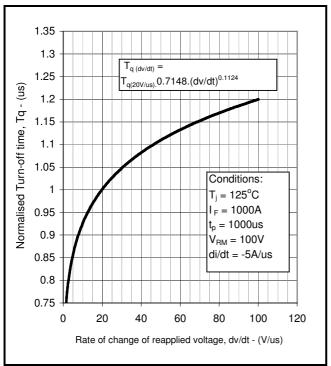


Fig.16 Turn-off time



PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

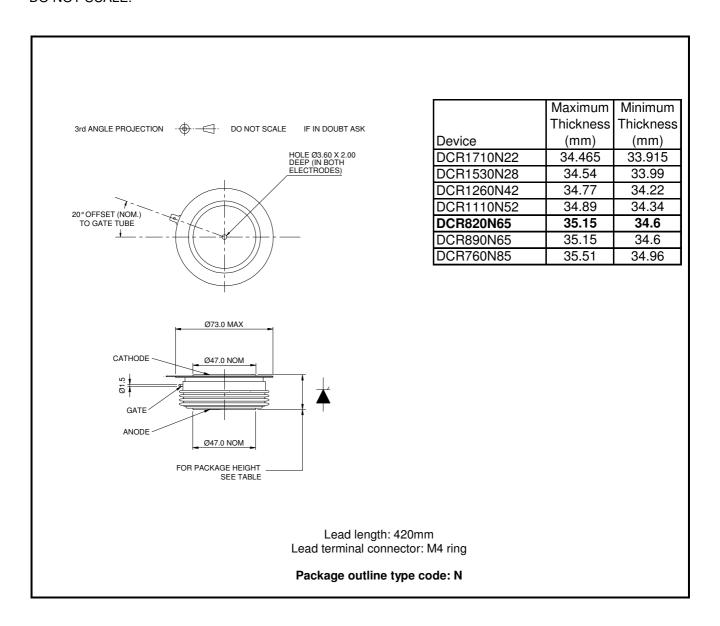


Fig.17 Package outline





POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



http://www.dynexsemi.com

e-mail: power solutions@dynexsemi.com

HEADQUARTERS OPERATIONS DYNEX SEMICONDUCTOR LTD

Doddington Road, Lincoln Lincolnshire, LN6 3LF. United Kingdom.

Tel: +44(0)1522 500500 Fax: +44(0)1522 500550 **CUSTOMER SERVICE**

Tel: +44(0)1522 502753 / 502901. Fax: +44(0)1522 500020

© Dynex Semiconductor 2003 TECHNICAL DOCUMENTATION – NOT FOR RESALE. PRODUCED IN UNITED KINGDOM.

This publication is issued to provide information only which (unless agreed by the Company in writing) may not be used, applied or reproduced for any purpose nor form part of any order or contract nor to be regarded as a representation relating to the products or services concerned. No warranty or guarantee express or implied is made regarding the capability, performance or suitability of any product or service. The Company reserves the right to alter without prior notice the specification, design or price of any product or service. Information concerning possible methods of use is provided as a guide only and does not constitute any guarantee that such methods of use will be satisfactory in a specific piece of equipment. It is the user's responsibility to fully determine the performance and suitability of any equipment using such information and to ensure that any publication or data used is up to date and has not been superseded. These products are not suitable for use in any medical products whose failure to perform may result in significant injury or death to the user. All products and materials are sold and services provided subject to the Company's conditions of sale, which are available on request.

All brand names and product names used in this publication are trademarks, registered trademarks or trade names of their respective owners